

SOCKET ASSEMBLY FOR TEST OF INTEGRATED CIRCUIT, AND ITS
INTEGRATED CIRCUIT AND TESTER

ABSTRACT OF THE DISCLOSURE

5 A socket assembly for an integrated circuit test, and its integrated circuit and tester, are provided to select a direct or indirect connection of an integrated circuit to a test board. This configuration provides increased efficiency, and reduced load capacity through direct connection so as to increase 10 reliability of an electrical characteristic test. The socket assembly includes a guide block, a guide part and a pressurizing plate. The guide block is in a terminal region of a test board, the guide block defining an area into which an integrated circuit can be inserted opposite terminals formed on the test 15 board in the terminal region. The guide part is provided on an inner side wall of the guide block, to guide an insertion position of the integrated circuit so that respective leads of the integrated circuit are aligned with the corresponding terminals of the test board. The pressurizing plate is adapted 20 to interface with the guide block, the pressurizing plate including a pressurizing protrusion on a surface thereof, such that when the pressurizing plate is applied to the guide block, the respective leads of the integrated circuit are urged to connect with the corresponding terminals of the test board.

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